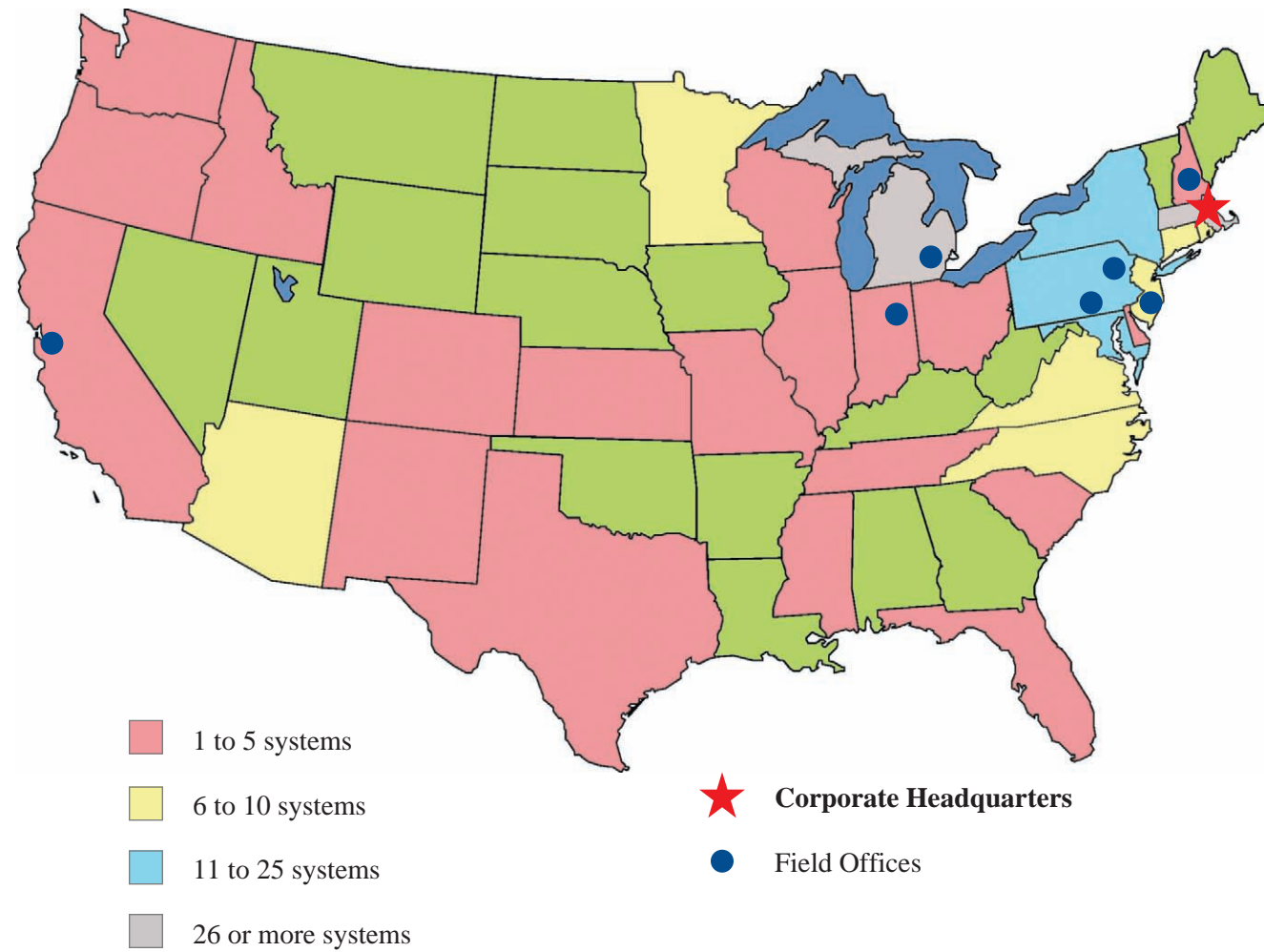


U.S. Sales, Service, and System Locations



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Specializing in E-Beam Products

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SEMTECH SOLUTIONS (STS) IS AN ESTABLISHED AND KNOWLEDGEABLE PROVIDER OF RECONDITIONED SCANNING ELECTRON MICROSCOPES AND SEM SERVICES, ACCESSORIES, PARTS, AND EQUIPMENT

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Our used SEMs are a cost effective alternative to buying a new instrument. Our models include field emission, tungsten, and LaB6. Each instrument is restored, calibrated, and tested. Our goal is to provide your company with the right instrument for the best value.

X-Stream Imaging System

The X-Stream Imaging System provides users of old reliable analog SEMs with a package that will "stream" live images to a PC via a USB 2.0 connection. Our USB X-Stream Imaging System will give your SEM the digital makeover it has been needing, guaranteed!



STS IS THE NORTH AMERICAN SALES REPRESENTATIVE FOR ELIONIX, THE LEADING SUPPLIER OF ELECTRON BEAM LITHOGRAPHY SYSTEMS IN ASIA

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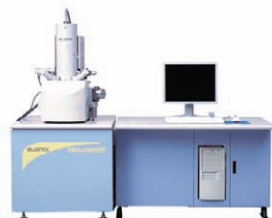


Elionix ELS-7X00 EBL Systems

The Elionix ELS-7000 is an Electron Beam Lithography system with a maximum acceleration voltage of 100kV. It employs an unsurpassed 1.8 nm electron beam diameter, which results in line width patterns of less than 8 nm. Also available is an ELS-7500EX with a maximum acceleration voltage of 50 kV and a new ELS-7800 with 80 kV.

Elionix 3D e-RAM

The Elionix Electron Roughness Analyzing Microscope is a unique tool that incorporates 4 secondary-electron detectors to provide high resolution 3-D topographical imaging. The system has multiple modes that provide a z measurement resolution of 1 nm and conventional SEM images. EDS is also available as an option.



Elionix ENT-2100 Nanoindenter

The ENT-2100 enables hardness measurements of soft polymer materials, thin multi-layered films, and next generation magnetic media. Excellent measurement repeatability of these materials are realized at indentation depths of several nanometers. Hardness tests can be made at a minimum load of 1 μ N.



STS IS THE NORTHEAST SALES REPRESENTATIVE FOR PHYSICAL ELECTRONICS, THE WORLD'S LEADING SUPPLIER OF SURFACE ANALYSIS INSTRUMENTATION

www.phi.com



PHI 700 Scanning Auger Nanoprobe

The PHI 700 Scanning Auger Nanoprobe provides elemental and chemical analysis of sample surfaces. It offers a 6 nm SE image resolution, 8 nm Auger resolution, and stable imaging at 500,000X magnification.

PHI ADEPT-1010 Dynamic SIMS

The PHI ADEPT-1010 is a Quadruple Dynamic SIMS tool capable of depth profiling in industries using thin films, insulating materials, and semiconductor implant technologies. It provides the highest performance low voltage depth profiling, lowest detection limits for contaminants, and highest efficiency extraction optics.



PHI TRIFT V nanoTOF™ SIMS

The PHI TRIFT V nanoTOF is based on PHI's patented TRIFT mass spectrometer technology that provides imaging with minimal shadowing on samples with high surface topography and the highest commercially available mass resolution performance. The system includes a revolutionary new sample introduction chamber which allows the user to perform analysis of both surface mounted or back loaded specimens.



PHI Quantera Scanning X-Ray Microprobe

PHI's Innovative Scanning X-Ray Microprobe has redefined XPS. The patented focused scanning x-ray source (as small as 9 μ m) provides a SEM-like environment for performing micro-area XPS analysis. The Quantera comes with a highly productive user-friendly instrument platform.



PHI 5000 VersaProbe™ XPS

The PHI 5000 VersaProbe is a multi-technique surface analysis instrument. Based on PHI's highly successful scanning x-ray microprobe technology, the VersaProbe provides high performance micro-area spectroscopy, chemical imaging, and secondary electron imaging with a raster scanned 10 μ m diameter x-ray beam. In addition, PHI's patented dual beam charge neutralization method provides effortless analysis of insulating samples.



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